

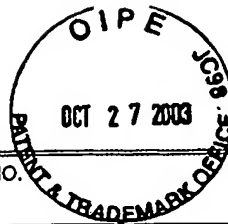


**LIST OF RELATED CASES**

	<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
01	240733US0*	10/626,612	07/25/03	IKEDA, et al.
01	240899US-0-PCT	10/470,752	07/31/03	KASHIMA, et al.
01	228930US0	10/262,317	10/02/02	IKEDA, et al.
01	198244US0	6,306,527	10/23/01	IKEDA, et al.
01	00023-1786-0	6,316,127	11/13/01	IKEDA, et al.
01	00023-1731-0- CONT	6,280,538	08/21/01	SOSHIRODA, et al.
01	223696US0	10/157,071	05/30/02	UTSUMI, et al.
01	239964US0	10/614,821	07/09/03	AKAMIZU, et al.

Deborah Yee 2-9-05

\*Present Application; listed for information  
NFO/amr



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240733US0		SERIAL NO. 10/626,612	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shushi IKEDA, et al.			
				FILING DATE July 25, 2003		GROUP 1700	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
DY 07 07	AA	6,306,527	10-23-01	IKEDA et al.	—	—	
	AB	6,316,127	11-13-01	IKEDA et al.	—	—	
	AC	6,280,538	08-28-01	SOSHIRODA et al.	—	—	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner Deborah Yee					Date Considered 2-9-05		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 240733US0		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Shushi IKEDA, et al.			
				FILING DATE Herewith		GROUP 1700	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
04	AO	60-43425	03/08/85	Japan			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <u>Deborah Yell</u>					Date Considered <u>2-9-05</u>		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
DY 258075US0X	10/928,176	08/30/04		KASHIMA, et al.
DY 240733US0*	10/626,612	7/25/03	US 2004-0159373 A1	IKEDA, et al.

Deborah Yee 2-9-05

\*Present Application; listed for information  
NFO/hah/get



**LIST OF RELATED CASES**

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
248711US0	10/785,080	02/25/04	IKEDA, et al.
240733US0*	10/626,612	07/25/03	IKEDA, et al.

Deborah Lee 2-9-05

\*Present Application; listed for information  
NFO/amr/wal